SHARP PT550/PT550F

PT550/PT550F

TO-18 Type Phototransistor with Base Terminal

■ Features

1. High sensitivity

PT550 $I_C : MIN.3mA \text{ at E }_e = 0.1 \text{mW/cm}^2$ **PT550F** I_C : MIN.3mA at E $_{e} = 1 \text{mW/cm}^{2}$

2. Narrow acceptance: PT550

 $(\Delta \theta : TYP. \pm 6^{\circ})$

Wide acceptance: PT550F

 $(\Delta \theta : TYP. \pm 50^{\circ})$

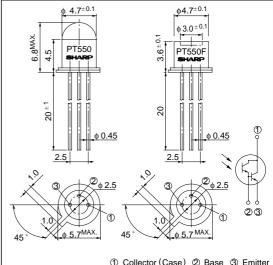
3. TO - 18 type standard package

■ Applications

- 1. Optoelectronic switches, optoelectronic counters
- 2. Smoke detectors
- 3. Infrared applied systems

■ Outline Dimensions

(Unit: mm)



① Collector (Case) ② Base ③ Emitter

■ Absolute Maximum Ratings

 $(Ta = 25^{\circ}C)$

Parameter	Symbol	Rating	Unit	
Collector-emitter voltage	V _{CEO}	35	V	
Emitter-collector voltage	V ECO	6	V	
Collector-base voltage	V _{CBO}	V CBO 35		
Collector current	$I_{\rm C}$	100	mA	
Collector power dissipation	P _C	150	mW	
Operating temperature	T opr	- 25 to + 125	°C	
Storage temperature	T stg	- 55 to +150	°C	
*1 Soldering temperature	T sol	260	°C	

^{*1} For 10 seconds at the position of 1.3mm from the bottom face of can package

■ Electro-optical Characteristics

 $(Ta = 25^{\circ}C)$

Parameter		Symbol	Conditions		MIN.	TYP.	MAX.		Unit
			PT550	PT550F	WIIIN.	IIP.	MAA.		UIII
*2Collector curr	ent	$I_{\rm C}$	$V_{CE} = 5V$ $E_e = 0.1 \text{mW/cm}^2$	$V_{CE} = 5V$ $E_e = 1mW/cm^2$	3	20	PT550 PT550F	142 150	mA
Collector dark	current	I _{CEO}	$V_{CE} = 10V, E_e = 0, I_B = 0$		-	10-7	10-6		A
Collecter-emitter saturation voltage		V _{CE(sat)}	$I_C = 1 \text{mA}, I_B = 0$ $E_e = 0.1 \text{mW/cm}^2$	$I_C = 1mA, I_B = 0$ $E_e = 1mW/cm^2$	-	-	1.0		V
Peak sensitivi	ty wavelength	λ_P	_		-	800	-		nm
Response	Rise time	t _r	$V_{CC} = 15V$, $I_C = 1mA$, $R_L = 1k\Omega$		-	350	-		μs
time	Fall time	t_{f}			-	300	-		μs

^{*2} E e : Irradiance by CIE standard light source A (tungsten lamp)

Fig. 1 Collector Power Dissipation vs.
Ambient Temperature

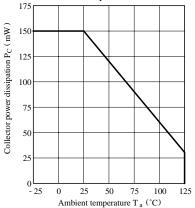


Fig. 3 Relative Collector Current vs.
Ambient Temperature

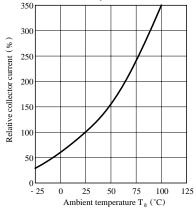


Fig.4-b Collector Current vs. Irradiance (PT550F)

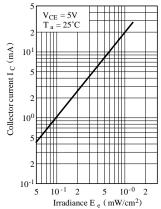


Fig. 2 Collector Dark Current vs.
Ambient Temperature

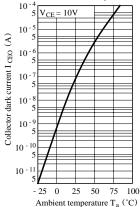


Fig.4-a Collector Current vs. Irradiance (PT550)

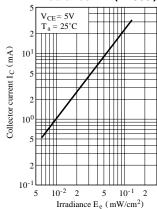


Fig.5-a Collector Current vs.
Collector-emitter Voltage

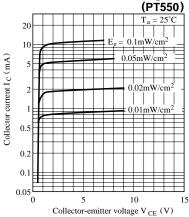




Fig.5-b Collector Current vs.
Collector-emitter Voltage

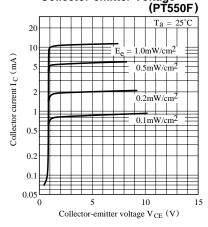


Fig. 7 Response Time vs. Load Resistance

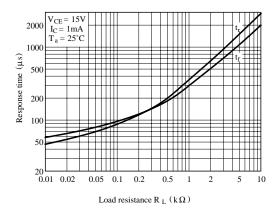


Fig.8-a Sensitivity Diagram (PT550) $(T_a = 25^{\circ}C)$

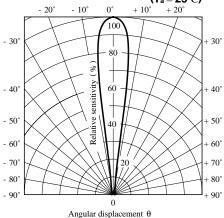
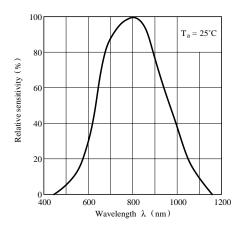


Fig. 6 Spectral Sensitivity



Test Circuit for Response Time

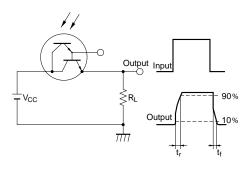
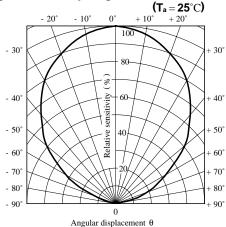


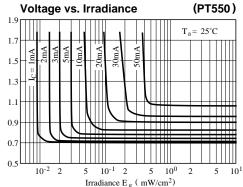
Fig.8-b Sensitivity Diagram (PT550F)



Collector-emitter saturation

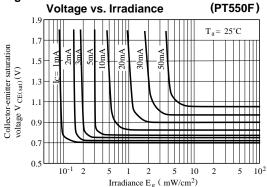
voltage V CE(sat)(V)

Fig.9-a Collector-emitter Saturation Voltage vs. Irradiance



• Please refer to the chapter "Precautions for Use."

Fig.9-b Collector-emitter Saturation Voltage vs. Irradiance



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